

RF Exposure Report

Report No.: SA171226E06

FCC ID: HV4-PN579X

Test Model: PN579X

Received Date: Dec. 26, 2017

Test Date: Feb. 02, 2018

Issued Date: Feb. 27, 2018

Applicant: Wacom Co., Ltd.

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- **Issued By:** Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch Hsin Chu Laboratory
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Release Control Record							
Issue No.	Description	Date Issued					
SA171226E06	Original release.	Feb. 27, 2018					



1 Certificate of Conformity

Product:	Dell Premium Active Pen	
Brand:	Dell	
Test Model: PN579X		
Sample Status:	ENGINEERING SAMPLE	
Applicant:	Wacom Co., Ltd.	
Test Date:	Feb. 02, 2018	
Standards:	FCC Part 2 (Section 2.1093)	
	KDB 447498 D01 General RF Exposure Guidance v06	
	IEEE C95.1-1992	

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

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Approved by :	May Chen / Manager	, C	Date:	Feb. 27, 2018



2 Evaluation Result

Following FCC KDB 447498 D01 "General SAR test exclusion guidance"

The corresponding SAR Exclusion Threshold condition, listed below:

 The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\cdot [\sqrt{f(GHz)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where

- > f(GHz) is the RF channel transmit frequency in GHz.
- > Power and distance are rounded to the nearest mW and mm before calculation.
- The result is rounded to one decimal place for comparison The test exclusions are applicable only when the minimum test separation distance is < 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.
- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:
 - a) [Threshold at 50 mm in step 1) + (test separation distance 50mm)·(f(MHz)/150)] mW, at 100MHz to 1500 MHz
 - b) [Threshold at 50 mm in step 1) + (test separation distance 50 mm)·10] mW at > 1500 MHz and ≤ 6 GHz
- 3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.
 - a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by [1 + log(100/f(MHz))] for test separation distances > 50 mm and < 200 mm.
 - b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by ½ for test separation distances ≤ 50 mm.
 - c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.



3 SAR Test Exclusion Thresholds

BT-LE Avg. Power Table

Channel	Channel Frequency (MHz)		Power	Avg. Power	
		(mW)	(dBm)	(mW)	(dBm)
0	2402	1.542	1.88	1.528	1.84
19	2440	1.6	2.04	1.578	1.98
39	2480	1.528	1.84	1.507	1.78

For BT-LE SAR Test Exclusion Thresholds

Frequency (GHz)	Max Avg. Power (dBm)	*Max Time Avg. Power (dBm)	Max Time Avg. Power (mW)	Min. test separation distance (mm)	SAR test exclusion calculation value ^(NOTE 1)	10-g SAR test exclusion thresholds	Result
2.402 ~ 2.480	1.98	0.21	1.05	5	0.328	7.5	Pass

NOTE: 1. The antenna type is chip antenna with 1.5dBi gain.

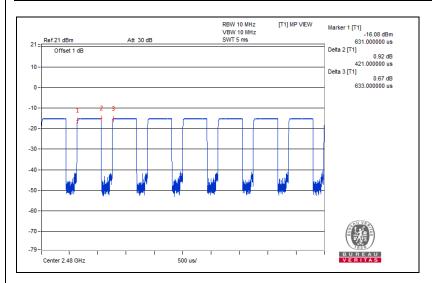
2. Calculate SAR test exclusion thresholds from condition "1" formulas.

3. *Time Avg. Power= Avg. Power+Duty factor

BT-LE Duty Cycle of Test Signal

Duty Cycle	Tx on	Tx total	Duty Factor
	(ms)	(ms)	(dB)
, ,	0.421	0.663	-1.77

Duty Factor =10 * log(Tx on / Tx total)



4 Conclusion

Since Source-base time average power is below SAR test exclusion power thresholds, the SAR evaluation is not required.

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